

FIG. 1

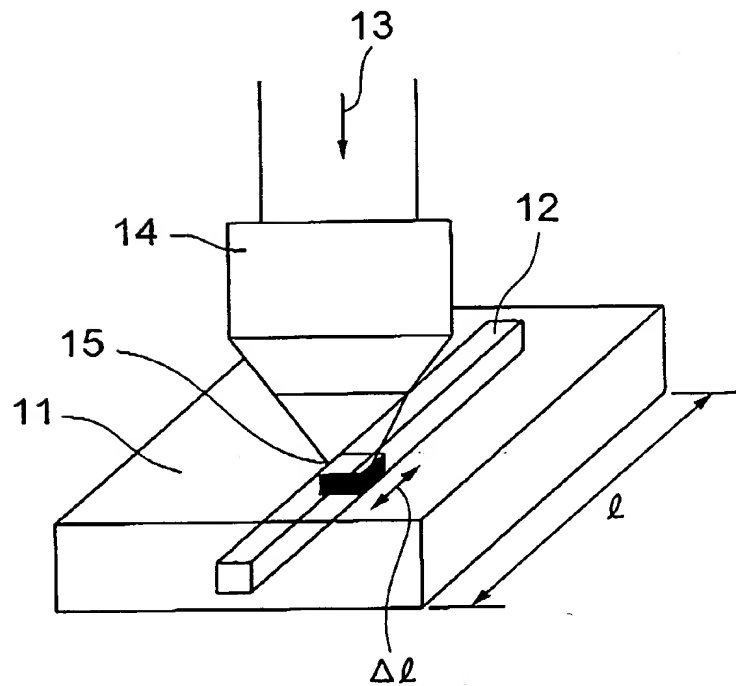


FIG. 2

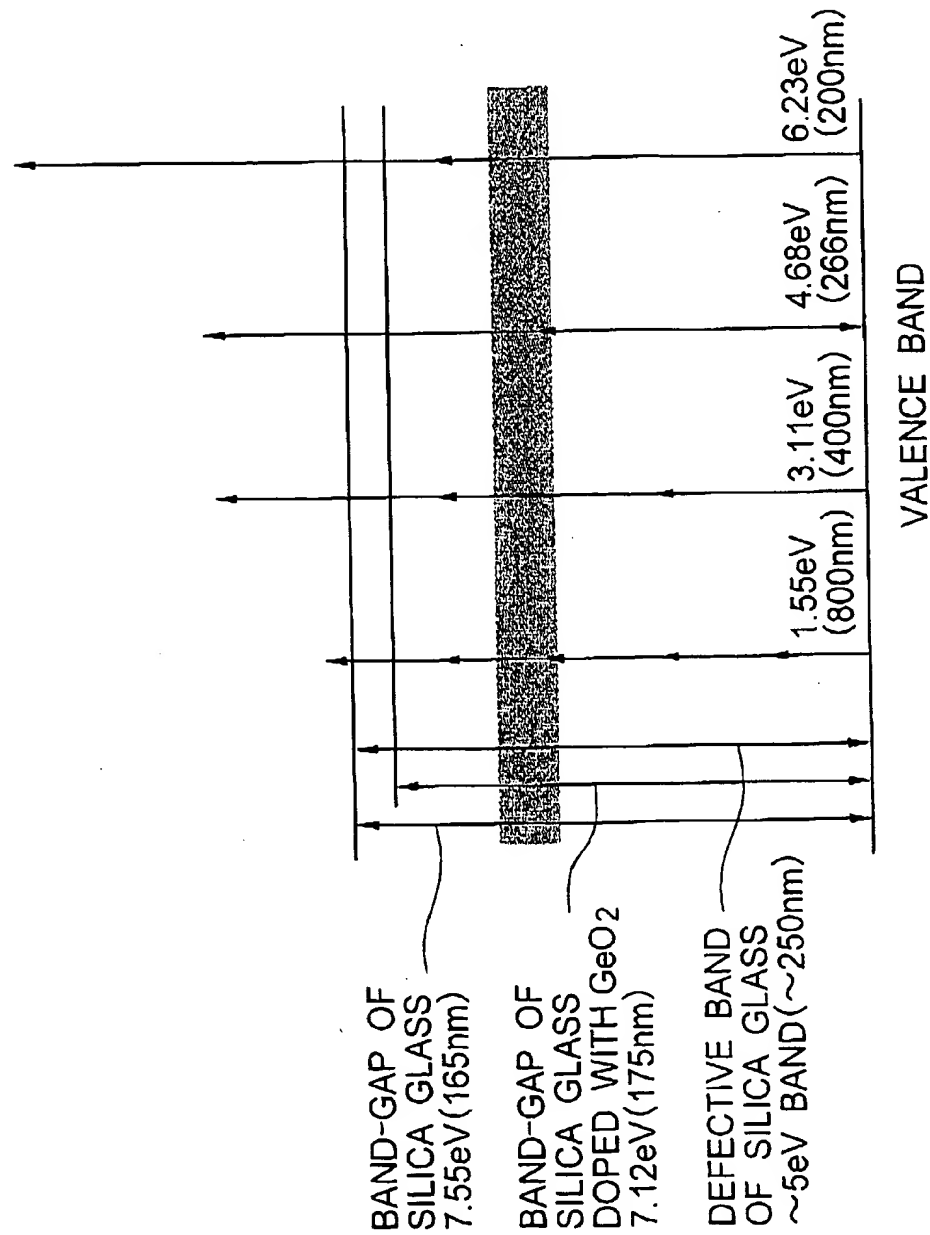


FIG. 3

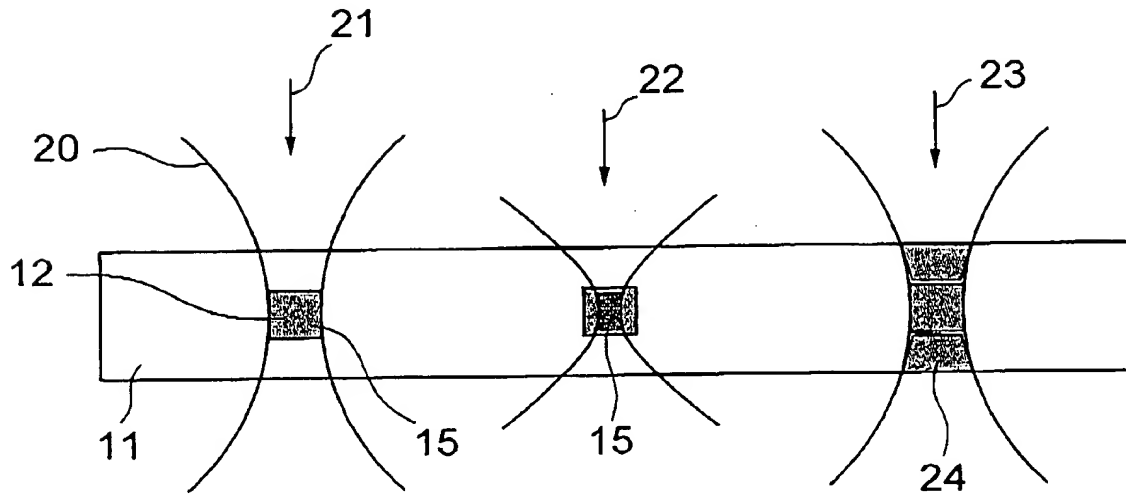


FIG. 4

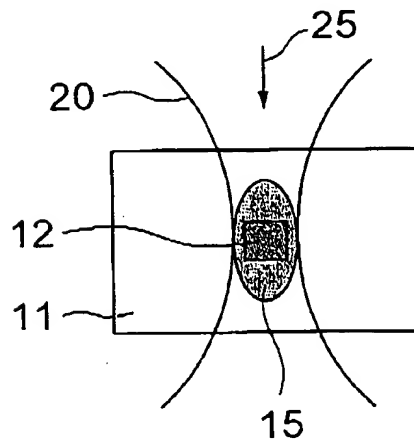


FIG. 5

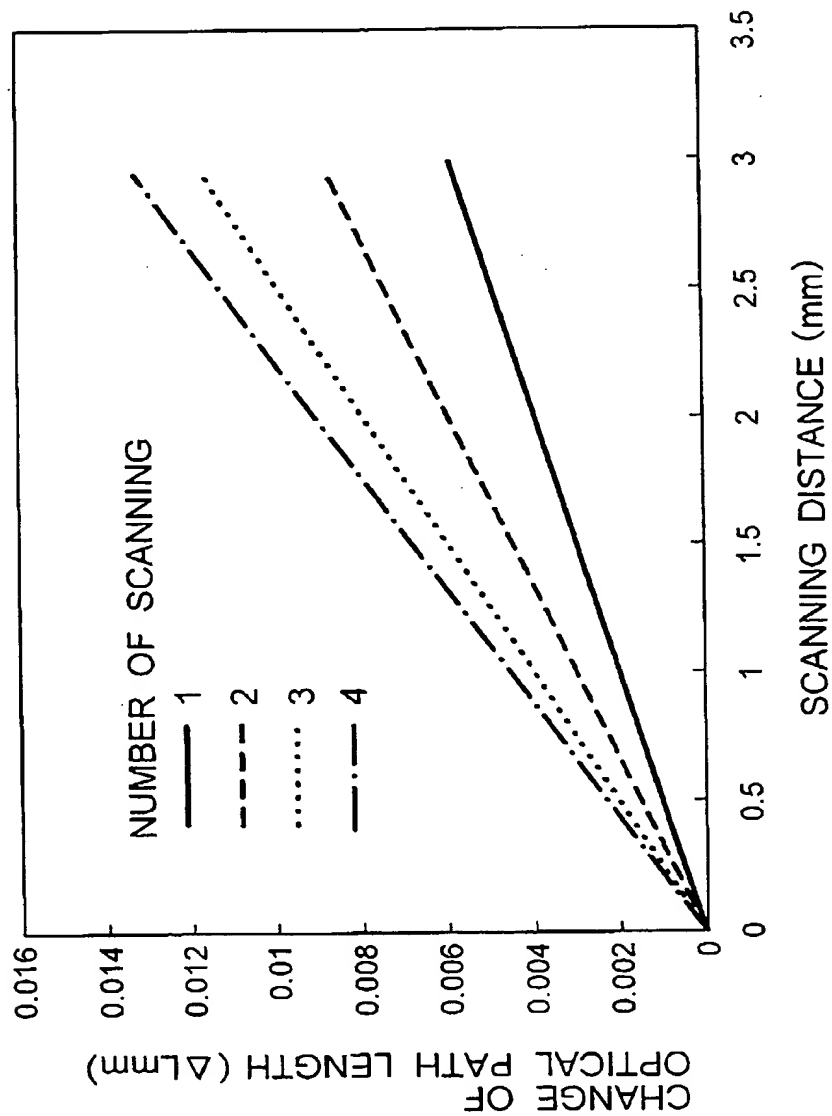


FIG. 6

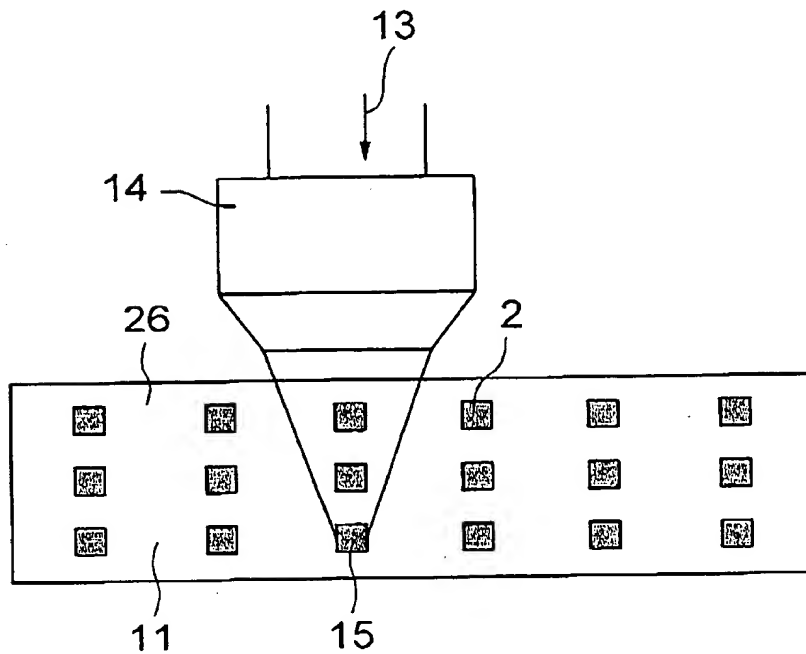


FIG. 7

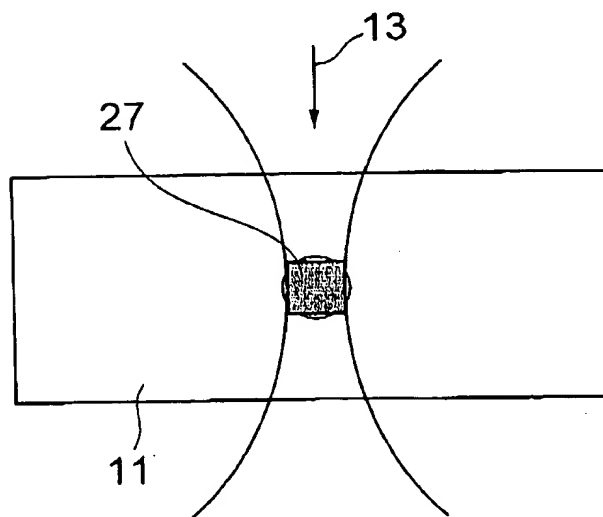


FIG. 8

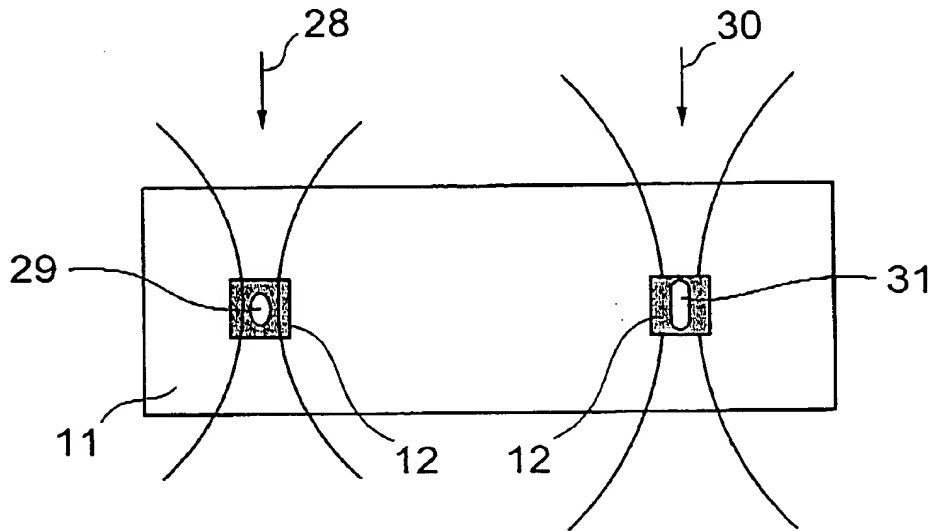


FIG. 9

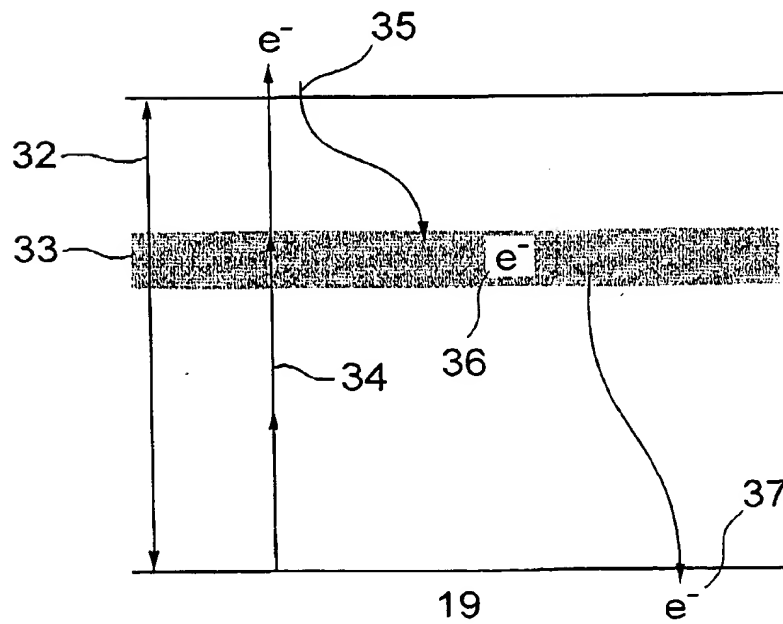


FIG. 10

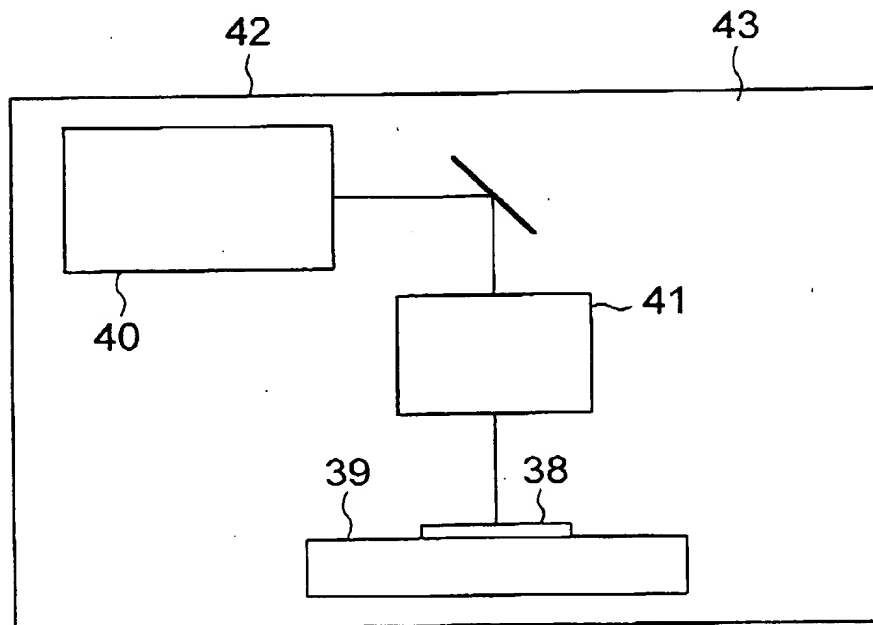


FIG. 11

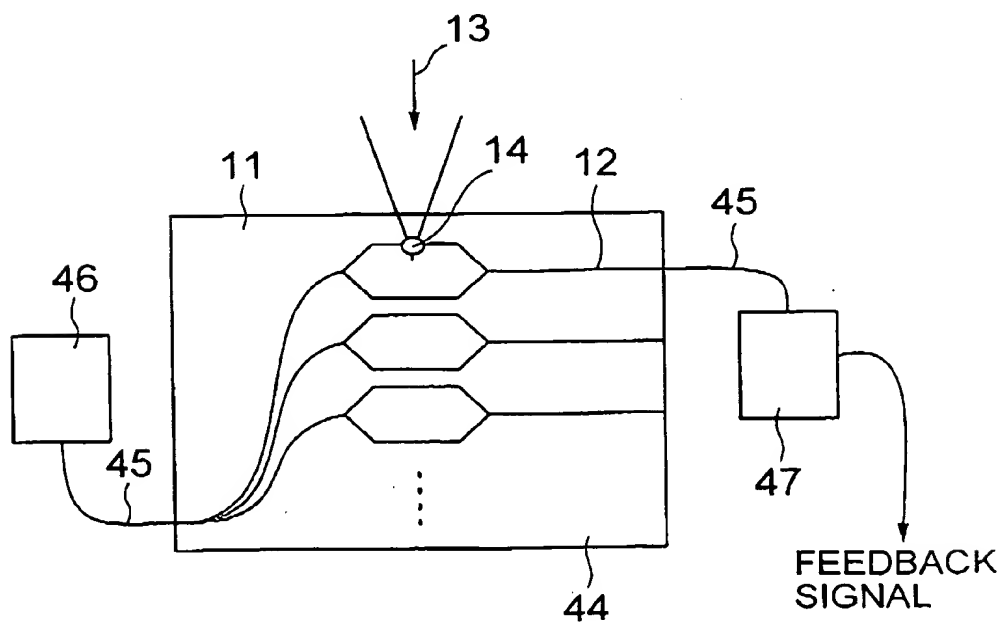


FIG. 12

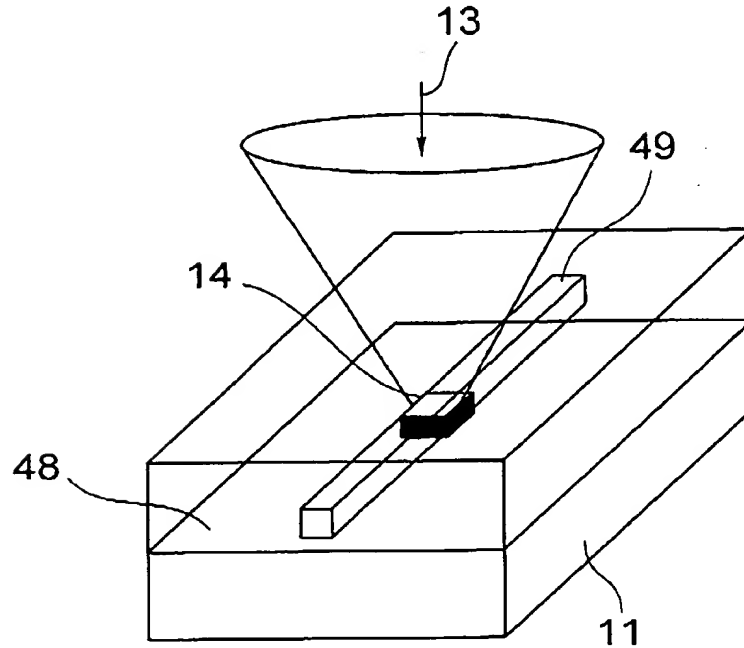


FIG. 13

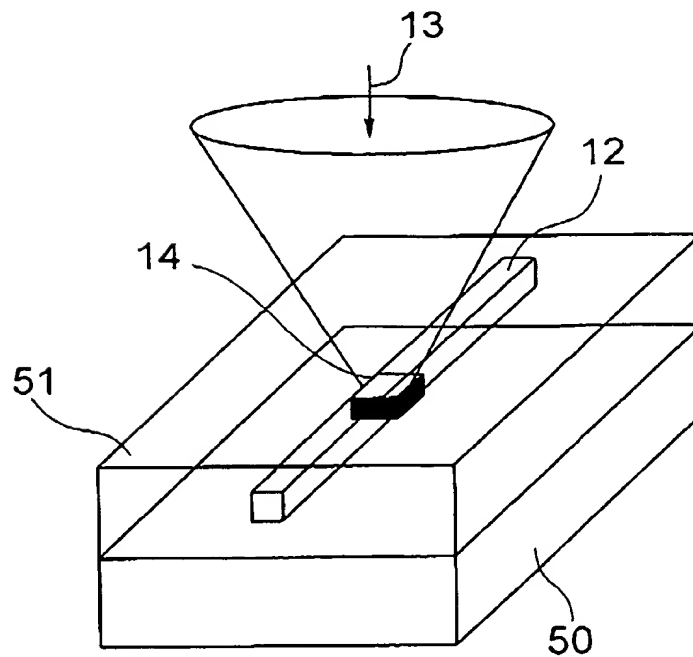




FIG. 14

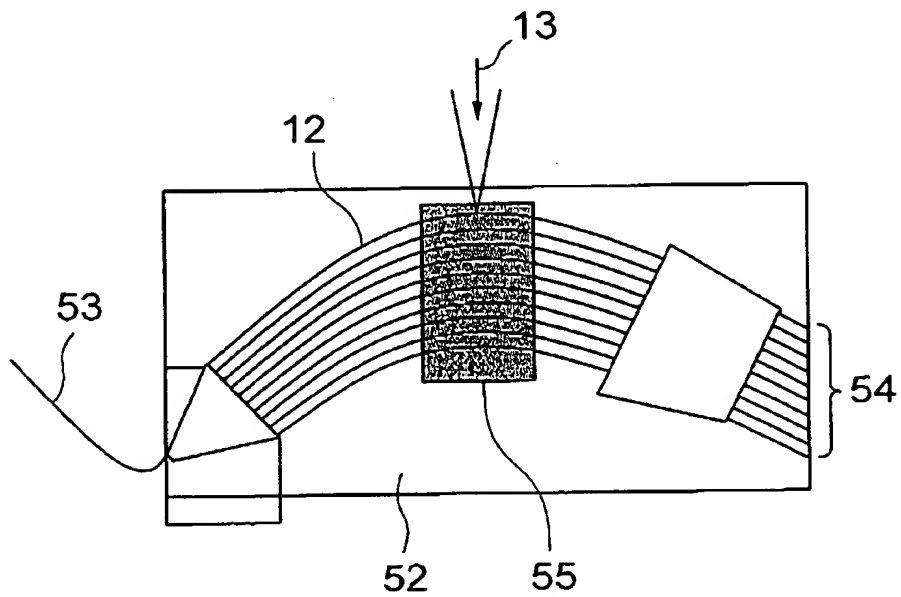
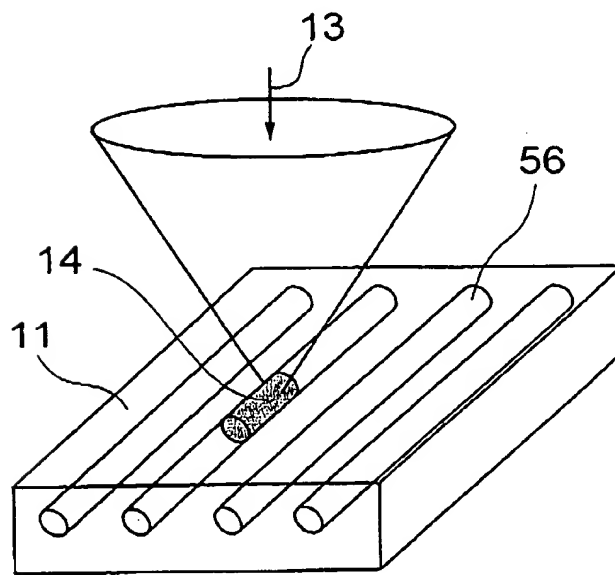


FIG. 15



A cross-sectional diagram of a scanning probe tip (13) scanning a sample surface (12). The tip is shown in contact with the surface, with a scanning direction indicated by an arrow labeled "SCANNING". The tip is labeled 13, the sample surface is 12, and the contact area is 14. A layer 50 is shown beneath the surface, and a feature 51 is indicated on the surface.

FIG. 18

